# **BUSTECH 2017**

## Forward

The Seventh International Conference on Business Intelligence and Technology (BUSTECH 2017), held between February 19-23, 2017 in Athens, Greece, continues a series of events covering topics related to business process management and intelligence, integration and interoperability of different approaches, technology-oriented business solutions and specific features to be considered in business/technology development.

We take here the opportunity to warmly thank all the members of the BUSTECH 2017 technical program committee, as well as all the reviewers. We also kindly thank all the authors that dedicated much of their time and effort to contribute to BUSTECH 2017. We truly believe that, thanks to all these efforts, the final conference program consisted of top quality contributions.

We also gratefully thank the members of the BUSTECH 2017 organizing committee for their help in handling the logistics and for their work that made this professional meeting a success.

We hope that BUSTECH 2017 was a successful international forum for the exchange of ideas and results between academia and industry and to promote further progress in the area of business intelligence and technology. We also hope that Athens, Greece provided a pleasant environment during the conference and everyone saved some time to enjoy the charm of the city.

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